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APPLICATION NO.	FILING	DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
09/891,833	06/25/2001		Steven Verhaverbeke	004730	2675
32588	7590	05/20/2004		EXAMINER	
APPLIED M		JOLLEY, KIRSTEN			
2881 SCOTT BLVD. M/S 2061 SANTA CLARA, CA 95050				ART UNIT	PAPER NUMBER
	,			1762	

DATE MAILED: 05/20/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

•	Application No.	Applicant(s)
Office Astion Comments	09/891,833	VERHAVERBEKE ET AL.
Office Action Summary	Examiner	Art Unit
	Kirsten C Jolley	1762
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the	correspondence address
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply If NO period for reply is specified above, the maximum statutory period w Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be to within the statutory minimum of thirty (30) da will apply and will expire SIX (6) MONTHS from cause the application to become ABANDONI	mely filed ys will be considered timely. In the mailing date of this communication. ED (35 U.S.C. § 133).
Status		*
Responsive to communication(s) filed on <u>01 M.</u> This action is FINAL . 2b)⊠ This Since this application is in condition for allowar closed in accordance with the practice under E	action is non-final. nce except for formal matters, pr	
Disposition of Claims		
4) ⊠ Claim(s) 1-13 and 17 is/are pending in the app 4a) Of the above claim(s) is/are withdraw 5) □ Claim(s) is/are allowed. 6) ⊠ Claim(s) 1-10 and 17 is/are rejected. 7) ⊠ Claim(s) 11-13 is/are objected to. 8) □ Claim(s) are subject to restriction and/or	vn from consideration.	
Application Papers	•	
9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) acce Applicant may not request that any objection to the of Replacement drawing sheet(s) including the correction 11) The oath or declaration is objected to by the Ex	epted or b) objected to by the drawing(s) be held in abeyance. Se ion is required if the drawing(s) is ol	ee 37 CFR 1.85(a). ojected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
12) ☐ Acknowledgment is made of a claim for foreign a) ☐ All b) ☐ Some * c) ☐ None of: 1. ☐ Certified copies of the priority documents 2. ☐ Certified copies of the priority documents 3. ☐ Copies of the certified copies of the prior application from the International Bureau * See the attached detailed Office action for a list	s have been received. s have been received in Applicat ity documents have been receiv ı (PCT Rule 17.2(a)).	ion No ed in this National Stage
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal I 6) Other:	

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DETAILED ACTION

Response to Arguments/Amendments

- 1. The claim objections and 35 USC 112, 2nd paragraph rejections set forth in the prior Office action have been withdrawn in response to Applicant's amendments to the claims.
- 2. The 35 USC 102(b) rejection of claim 1 over Akimoto et al. and 35 USC 103(a) rejections of claims 1-3 over Blades have been withdrawn in response to Applicant's amendments to claim 1 which require that the measured amount of chemical is used in a semiconductor wafer cleaning process.
- 3. The 35 USC 103(a) rejections of claims 4 and 6-7 over Blades have been withdrawn in response to Applicant's argument that Blades fails to teach measuring one chemical and then measuring the amount of the chemical and dilutant mixture as claimed by Applicant.
- 4. The 35 USC 103(a) rejections of claims 11-13 over Toge have been withdrawn in response to Applicant's arguments that Toge fails to describe utilizing two *separate* valve systems having tubes of a known volume. It is noted that claim 11 has been interpreted as requiring that the first and second valve systems are separate.
- 5. Upon additional search of the claims as newly amended, the prior art of McConnell et al. (US 4,899,767) was found. Claims 1-10 and 17 are newly rejected over the McConnell et al. reference and therefore this action is made non-final.

Claim Objections

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6. Claims 1-3 and 11-13 are objected to because of the following informalities: In claim 1, line 2, it appears that the word --in-- is missing after "chemical". In claim 11, line 11, it appears that --water-- is missing after "DI". Appropriate correction is required.

Claim Rejections - 35 USC § 102

7. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 8. Claims 1, 3-4, 7 are rejected under 35 U.S.C. 102(b) as being anticipated by McConnell et al. (US 4,899,767).

McConnell et al. discloses a method of generating a measured amount of a chemical in a semiconductor wafer cleaning process comprising the steps of: flowing a chemical treatment fluid F1, F2, F3, etc. into a valve system comprising measuring tank 32 having a known volume; filling said tube with said chemical to generate a measured amount of chemical; and applying the measured amount of said chemical to a semiconductor wafer (col. 7-8). Measuring tank 32 is long and thin, for example 2 inches diameter by 52 inches length (col. 7, lines 38-40), which meets the limitation of a tube. Because the measuring system of McConnell et al. is operable via a plurality of valves, it meets the limitation of a valve system.

With respect to claim 3, McConnell et al. teaches in col. 12, lines 63-66, that each of the inlet valves is preferably a 3-port valve. Therefore, the valve system of McConnell et al. comprises at least two 3-port valves.

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McConnell et al. teaches that its process may be used with *one* or more semiconductor wafers in col. 13, lines 56-57, therefore McConnell et al. discloses a single semiconductor wafer cleaning process.

Alternatively, McConnell et al. also teaches a delivery system for special fluids such as HF comprising two consecutive 3-port valves to accurately control the amount of HF that is injected into a water flow stream in order deliver precise concentrations of HF to the semiconductor cleaning process (Figure 5 and col. 12, lines 9-62). This valve system of Figure 5 necessarily has a known volume, and the described process comprises the steps of filling the tube with a cleaning chemical to generate a measured amount of said chemical and applying the measured amount to a semiconductor wafer in a single semiconductor wafer cleaning process.

With respect to claims 4 and 7, McConnell et al. additionally teaches the steps of flowing DI water into said valve system and pushing the measured amount of chemical into a chamber with said DI water, and continuing to flow said DI water (and chemical) into said chamber until a predetermined level is reached in said chamber.

Claim Rejections - 35 USC § 103

- 9. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 10. Claims 2, 5-6, 8-10, and 17 are rejected under 35 U.S.C. 103(a) as being unpatentable over McConnell et al.

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As to claims 2 and 6, McConnell et al. lacks a teaching of the use of a 6-port valve in its valve system. McConnell et al. states in col. 6, lines 59-65 that "various multiport two- or three-position valves may be substituted in the loop for certain groups of two or more valves shown in the figures." McConnell et al. also states with regard to Figure 5, "a five port, four way valve may also be used in place of the two three port, 2 position valves" (col. 12, lines 44-46). Therefore, McConnell et al. suggests the replacement of numerous smaller valves with multi-port valves. It would have been obvious to have replaced two 3-port valves of McConnell et al. with a 6-port valve with the expectation of equivalent results since it is known that a 6-port valve may perform the same as two 3-port valve in succession.

With respect to claim 8, McConnell et al. teaches with respect to Figure 5 and col. 12, lines 9-62 a process comprising the steps of flowing DI water into first and second conduits, wherein the DI water in the first conduit flows into the valve system to push the measured amount of chemical into a third conduit, an combining the flow of said measured amount of chemical and said DI water in said third conduit with said flow of DI water in said second conduit, and dispensing said combined flow onto a semiconductor wafer.

Claims 5, 8-10, and 17 lack a teaching of applying the mixed chemical solution to a spinning wafer. McConnell et al. teaches a desire to provide uniform exposure of the wafer(s) treated to the cleaning solution in the process of its invention. It is well known in the semiconductor manufacturing art that spinning of wafers immersed in a treatment solution ensures that all areas of the semiconductor wafer are exposed equally to the treatment solution. It would have been obvious for one having ordinary skill in the art to have spun the

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semiconductor wafer(s) while immersed in the various cleaning solutions in McConnell et al.'s process in order to equally expose all areas of the wafer(s).

Allowable Subject Matter

11. Claims 11-13 would be allowable if rewritten or amended to overcome the objection set forth in this Office action. The prior art does not teach or fairly suggest flowing a chemical into a first valve system having a tube of known volume to generate a measured amount of chemical, flowing DI water into a second valve system having a tube of known volume to generate a measured amount of DI water, and flowing an inert gas into both first and second valve systems to push the measured amounts of chemical and DI water into a chamber where the DI water and chemical are mixed together, and where the first and second valve systems are separate.

Conclusion

12. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Kirsten C Jolley whose telephone number is 571-272-1421. The examiner can normally be reached on Monday to Thursday and every other Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Shrive P Beck can be reached on 571-272-1415. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Kirsten C Jolley Patent Examiner Art Unit 1762

kcj